

26th European Symposium on
Reliability of Electron Devices,
Failure Physics and Analysis

October 5-9, 2015,
Centre de congrès P. Baudis,
Toulouse (France)



Call for participation

We invite you to be part of the **ESREF 2015**, the 26th European Symposium on Reliability of Electron Devices, Failure Physics and Analysis, will take place in Toulouse (France) from 5th to 9th October 2015.

We have built up an exciting program from more than 250 submissions from all around the world on recent developments and future directions in Quality and Reliability Management of materials, devices and circuits for micro-, nano-, and optoelectronics.

ESREF is the European forum for developing all aspects of reliability management and innovative analysis techniques for present and future electronic applications.

ESREF 2015 will be held for the first time in Toulouse, world center for aeronautics with Airbus assembly line, European capital of the space industry and number 1 in France for embedded electronic systems with a specific focus on related topics.

What we have setup for you

Build your own ESREF: we have topically structured ESREF to fit with your concerns whatever they are. Each (**Failure Analysis, Reliability, Power, FIB, Aerospace ...**) track has a continuous path with tutorial, invited paper, workshop, oral and poster session. If you like better **outstanding papers track**, we have 2 excellent keynotes, 3 best exchange papers (ISTFA, IPFA and IRPS) and 9 invited papers (none in parallel).

Do not forget the **exhibition that will be the center of the conference** with plenty of dedicated time to enjoy demos and technical discussions with exhibitors.

We also embedded a lot of tutorials giving attendees a **unique opportunity to attend all the 7 tutorials** (more than 10 hours). We are also building **pre-event (lab tours)** and **post-event (industry tours)** and a lot of **social networking activities** (workshops, expo and social event).

Look at the program at a glance (next page) and often browse our web site: <http://www.esref2015.org> for updated information and more details.

ESREF Organization and sponsoring



Conference program at a glance

Monday, October 5, 2015	
Plenary session - Cassiopée Room	
14:00	OFFICIAL OPENING
14:20	Keynote 1: ChemCam instrument on the Curiosity rover: from R&D to operations on Mars ; be reliable or die... - Sylvestre MAURICE, IRAP (France)
15:20	Expo intro & coffee break in exhibition area
16:20	Keynote 2: Towards Hardware Cyber security - Ramesh KARRI, Polytechnic Institute New York Univ. (USA)
17:20	Exchange Best IRPS/IPFA/ISTFA papers
18:40-21:00	POSTER SESSION - Cocktail/buffet in exhibition area

Tuesday, October 6, 2015				
8:00	SESSION: Space, Aeronautic & Embedded Systems	TUTORIAL: 1 Packaging & Assembly	WORKSHOP: Advanced reliability tools & techniques	SESSION: Failure analysis
		SESSION: Packaging & Assembly	TUTORIAL MEMS	WORKSHOP: Advanced FA tools & techniques
10:20	Coffee break in exhibition area			
10:40	SESSION: Space, Aeronautic & Embedded Systems	SESSION: Packaging & Assembly	Research Students Speed Dating	WORKSHOP: Gold Sponsor SECTOR TECHNOLOGIES
12:20	POSTER SESSION & Buffet in exhibition area			
13:20	WORKSHOP: Space, Aeronautic & Embedded Systems	SESSION: Packaging & Assembly	SESSION: Photonics	WORKSHOP: Gold Sponsor SECTOR TECHNOLOGIES
		TUTORIAL 2: Packaging & Assembly		
16:00	Coffee break in exhibition area			
16:20-18:00	TUTORIAL: Space, Aeronautic & Embedded Systems	SESSION: MEMS, MOEMS, NEMS & Nano-objects	SESSION: Photovoltaic & Organic Devices	WORKSHOP: Advanced FA tools & techniques
18:30	Welcome cocktail at TOULOUSE City Hall			

Wednesday, October 7, 2015				
8:00	SESSION: Failure analysis	SESSION: Photonics	ROUND TABLE: Quality & Reliability Assessment	SESSION: Si-Nano : Hot carriers, high K, gate materials
	WORKSHOP: Advanced FA tools & techniques		WORKSHOP: Quality & Reliability Assessment	SESSION: Si-Nano : ESD, Latch-up, Radiation Effects
10:20	Coffee break in exhibition area			
11:00	SESSION: Failure analysis	SESSION: Wide Band-gap Devices	WORKSHOP: Quality & Reliability Assessment	SESSION: Si-Nano : ESD, Latch-up, Radiation Effects
12:20	POSTER SESSION & Buffet in exhibition area			
14:20	TUTORIAL: Failure analysis	SESSION: Wide Band-gap Power Devices	SESSION: Quality & Reliability Assessment	SESSION: Si-Nano : ESD, Latch-up, Radiation Effects
16:00	Coffee break in exhibition area			
16:40-18:20	WORKSHOP: EUFANET	TUTORIAL: Power Devices	SESSION: Quality & Reliability Assessment	SESSION: Si-Nano : ESD, Latch-up, Radiation Effects
			WORKSHOP: Advanced FA tools & techniques	
19:00	GALA DINNER			

Thursday, October 8, 2015				
8:00	SESSION: Power Devices	SESSION: EFUG	SESSION: Quality & Reliability Assessment	
10:20	Coffee break in exhibition area			
11:00	SESSION: Power Devices	WORKSHOP: EFUG	TUTORIAL: Quality & Reliability Assessment	
12:40	POSTER SESSION & Buffet in exhibition area			
15:20	SESSION: Power Devices	WORKSHOP: EFUG	SESSION: Quality & Reliability Assessment	
17:40	PLENARY SESSION: CLOSING CEREMONY			

Friday, October 9, 2015		
8:30	WORKSHOP ECPE: Reliability of avionics power electronics	WORKSHOP: Design for Reliability
10:20	Coffee break	
10:40 - 12:30	WORKSHOP ECPE: Reliability of avionics power electronics	WORKSHOP: Design for Reliability